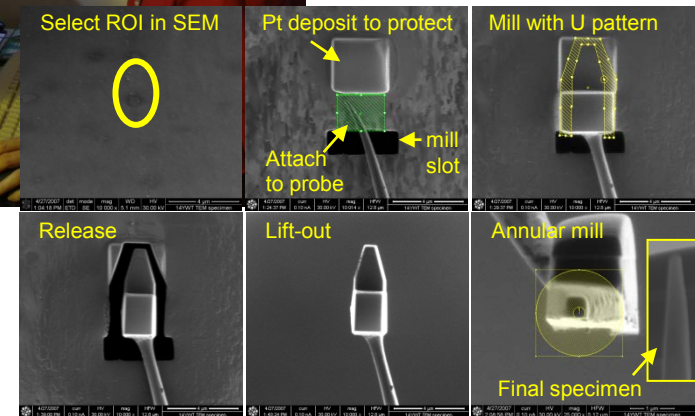
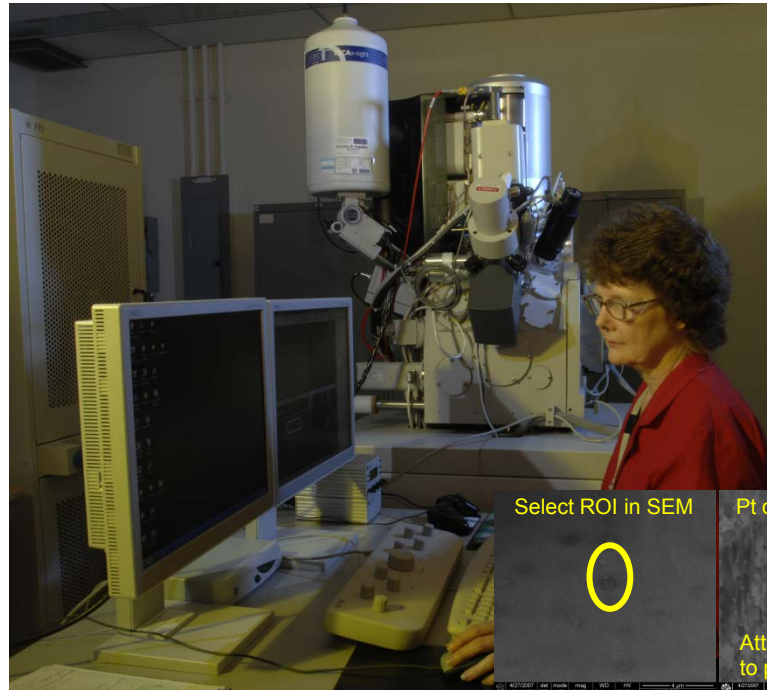


# FEI Nova 200 Dual-Beam SEM/FIB

## Capabilities:

- FEG scanning electron microscope
- Ion column with Ga liquid ion source for milling
- GIS for Pt deposition
- Kleindiek nanomanipulator for specimen lift-out
- Oxford Inca EDS system
- AutoTEM, AutoFIB, and slice and view automation software



Fabricating AP specimen from TEM foil

## Current Research Activities:

- Support instrument for atom probe and TEM specimen preparation
- 3D reconstruction of microstructural features

Contact: Jon Poplawsky, [poplawskyjd@ornl.gov](mailto:poplawskyjd@ornl.gov), (865) 576-4965